

**Notice of References Cited**

Application/Control No.

10/737,281

Applicant(s)/Patent Under  
Reexamination  
WEI ET AL.

Examiner

MICHAEL D. PHAM

Art Unit

2167

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0071379	03-2005	Kekre et al.	707/200
*	B	US-2003/0093443	05-2003	Huxoll, Vernon F.	707/204
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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**NON-PATENT DOCUMENTS**

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